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MATERIALS SCIENCE APPLICATIONS

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Direct Visualization of the Earliest Stages of Crystallization

Manish Kumar Singh, Chanchal Ghosh, Benjamin Miller and C. Barry Carter

Time the Control of the Control of the Control of the Control

Molybdenum in Gunshot Residue: Experimental Evidences and Detection Challenges in the Presence of Lead and Sulfur

Felice Nunziata, Francesco Saverio Romolo, Bryan Burnett, Luigi Manna, Stefano Orsenigo and Matteo Donghi

Quantitative 3D Characterization of Nanoporous Gold Nanoparticles by Transmission Electron Microscopy

Christoph Mahr, Alexandra Dworzak, Marco Schowalter, Mehtap Oezaslan and Andreas Rosenauer

678

659

666

Behavior of the ε -Ga $_2$ O $_3$:Sn Evaporation During Laser-Assisted Atom Probe Tomography

Florian Chabanais, Enrico Di Russo, Alexander Karg, Martin Eickhoff, Williams Lefebvre and Lorenzo Rigutti

687

Quantification of Trace-Level Silicon Doping in $Al_xGa_{1-x}N$ Films Using Wavelength-Dispersive X-Ray Microanalysis

Lucia Spasevski, Ben Buse, Paul R. Edwards, Daniel A. Hunter, Johannes Enslin, Humberto M. Foronda, Tim Wernicke, Frank Mehnke, Peter J. Parbrook, Michael Kneissl and Robert W. Martin

696

Evaluation of Dihedral Angle Twin Boundaries in Cu10 wt%Zn Alloy Using Atomic Force Microscopy

Nataliya Starostina, Ann McGuire and Richard Rowan

705

SOFTWARE AND INSTRUMENTATION

py4DSTEM: A Software Package for Four-Dimensional Scanning Transmission Electron Microscopy Data Analysis

Benjamin H. Savitzky, Steven E. Zeltmann, Lauren A. Hughes, Hamish G. Brown, Shiteng Zhao, Philipp M. Pelz, Thomas C. Pekin, Edward S. Barnard, Jennifer Donohue, Luis Rangel DaCosta, Ellis Kennedy, Yujun Xie, Matthew T. Janish, Matthew M. Schneider, Patrick Herring, Chirranjeevi Gopal, Abraham Anapolsky, Rohan Dhall, Karen C. Bustillo, Peter Ercius, Mary C. Scott, Jim Ciston, Andrew M. Minor and Colin Ophus

712

744

758

767

Scattering Matrix Determination in Crystalline Materials from 4D Scanning Transmission Electron Microscopy at a Single Defocus Value

Scott D. Findlay, Hamish G. Brown, Philipp M. Pelz, Colin Ophus, Jim Ciston and Leslie J. Allen

Quantifying Real-Time Sample Temperature Under the Gas Environment in the Transmission Electron Microscope Using a Novel MEMS Heater Meng Li, De-Gang Xie, Xi-Xiang Zhang, Judith C. Yang and Zhi-Wei Shan

Minimizing Crinkling of Soft Specimens Using Holey Gold Films on Molybdenum Grids for Cryogenic Electron Microscopy

Xi Jiang, Sunting Xuan, Ronald N. Zuckermann, Robert M. Glaeser, Kenneth H. Downing and Nitash P. Balsara

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an irradiated and annealed Gd2Ti2O7 sample from a 4D-STEM experiment. This sample exhibits complex structural features, including (left) single crystal structure of the pyrochlore parent grain recrystallized into fluorite at the interface, (center) a mixture of amorphous and newly nucleated polycrystalline grains, and (right) a fully amorphous structure. Image adapted from figures 1 and 10 in the manuscript

by Savitzky et al. on pages 714 and 726.

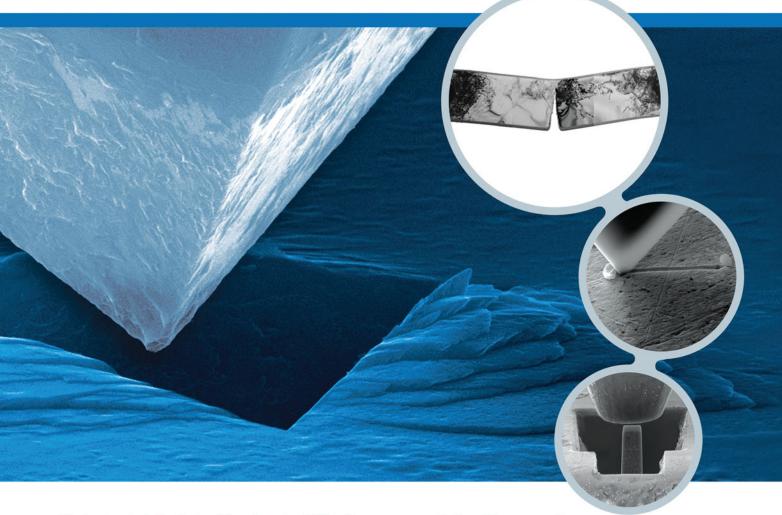
On the Cover: Structural phase map of

An Acquisition Parameter Study for Machine-Learning-Enabled Electron Backscatter Diffraction	776
Kevin Kaufmann and Kenneth S. Vecchio Fast Grain Mapping with Sub-Nanometer Resolution Using 4D-STEM with Grain	770
Classification by Principal Component Analysis and Non-Negative Matrix Factorization	
Frances I. Allen, Thomas C. Pekin, Arun Persaud, Steven J. Rozeveld, Gregory F. Meyers, Jim Ciston, Colin Ophus and Andrew M. Minor	794
Deep Learning Segmentation of Complex Features in Atomic-Resolution Phase-Contrast Transmission Electron Microscopy Images Robbie Sadre, Colin Ophus, Anastasiia Butko and Gunther H. Weber	804
Preparation of Samples for Large-Scale Automated Electron Microscopy of Tissue and Cell Ultrastructure	
Carsten Dittmayer, Hans-Hilmar Goebel, Frank L. Heppner, Werner Stenzel and Sebastian Bachmann	815
Focused Ion Beam Sample Preparation for <i>In Situ</i> Thermal and Electrical Transmission Electron Microscopy	
Dražen Radić, Martin Peterlechner and Hartmut Bracht	828
A Fast Algorithm for Scanning Transmission Electron Microscopy Imaging and 4D-STEM Diffraction Simulations	
Philipp M. Pelz, Alexander Rakowski, Luis Rangel DaCosta, Benjamin H. Savitzky, Mary C. Scott and Colin Ophus	835
BIOLOGICAL APPLICATIONS	
Immunofluorescence Image Feature Analysis and Phenotype Scoring Pipeline for Distinguishing Epithelial-Mesenchymal Transition	
Shreyas U. Hirway, Nadiah T. Hassan, Michael Sofroniou, Christopher A. Lemmon and Seth H. Weinberg	849
Mathematical Model and microCT-Based Kinematic Analysis of the Rostrum Mouthparts in <i>Cyrtotrachelus buqueti</i> Guer (Coleoptera: Curculionidae)	
Longhai Li, Ce Guo, Shun Xu, Huafeng Guo, Ping Yu, Lei Liu and Jing Tian	860
Early Upper Aerodigestive Tract Cancer Detection Using Electron Microscopy to Reveal Chromatin Packing Alterations in Buccal Mucosa Cells	
Oisín Bugter, Yue Li, Anouk H.G. Wolters, Vasundhara Agrawal, Amil Dravid, Andrew Chang, Jose Hardillo, Ben N.G. Giepmans, Robert J. Baatenburg de Jong, Arjen Amelink, Vadim Backman and Dominic J. Robinson	878
Effects of Iron Oxide Nanoparticles on Structural Organization of Hepatocyte Chromatin: Gray Level Co-occurrence Matrix Analysis	
Jovana Paunovic, Danijela Vucevic, Tatjana Radosavljevic, Biserka Vukomanovic Djurdjevic, Sanja Stankovic and Igor Pantic	889
Altered Renal Pathology in an Autoimmune Disease Mouse Model After Induction of Diabetes Mellitus	
Shiori Hiramatsu, Osamu Ichii, Takashi Namba, Yuki Otani, Teppei Nakamura, Md. Abdul Masum, Yaser Hosny Ali Elewa and Yasuhiro Kon	897
Pathological and Immunohistochemical Microscopy of Natural Cases of Canine and Feline Neoplastic Mammary Lesions	
Maggie F. Tawfik, Samah S. Oda and Asmaa F. Khafaga	910
Integrated Microscopy and Metabolomics to Test an Innovative Fluid Dynamic System for Skin Explants <i>In Vitro</i> Finite Cappallages, Serges Taggari, Manuala Malatata and Laura Caldaga.	923
Enrica Cappellozza, Serena Zanzoni, Manuela Malatesta and Laura Calderan	9L.
MICROGRAPHIA	
Histological, Histochemical, and Ultrastructural Approach to the Ductus Deferens in Male Nile Monitor Lizard (<i>Varanus niloticus</i>)	
Mahmoud Awad Mahammad Alchahri and Ahmad Saad A. Hassanson	035

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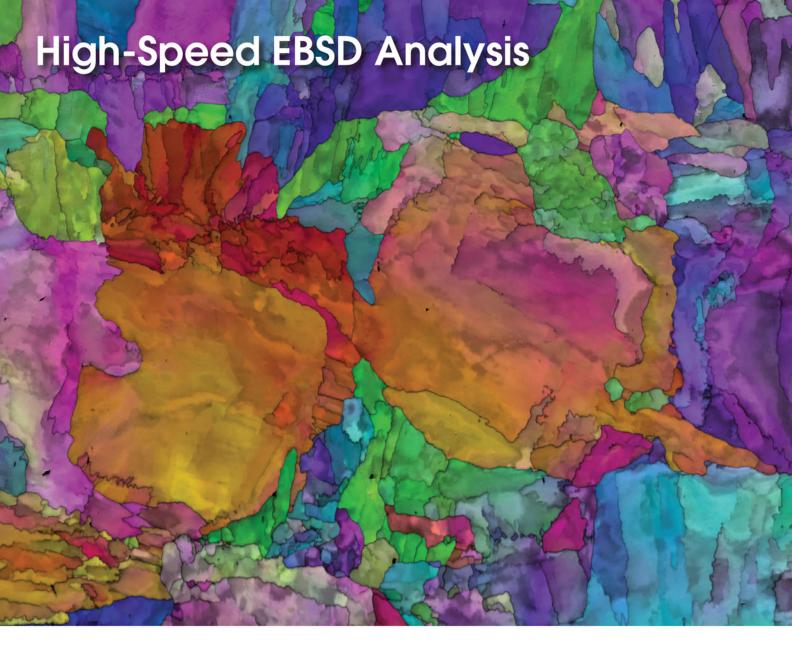




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